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Carrier type modulation and mobility improvement of thin MoTe₂

Abstract

Two dimensional semiconducting transition metal dichalcogenides (TMDCs) have attracted enormous attention recently.[1-4] This work describes the first systematic modulation of the carrier type in MoTe₂. Unipolar p- and ntype MoTe₂ FETs with 10⁵ and 10⁶ on-off ratios were achieved by using rapid thermal annealing (RTA) and Benzyl Viologen (BV) doping respectively. MoTe₂ is ultra-sensitive to O₂ at elevated temperatures (250°C). MoTe₂ was annealed via rapid thermal annealing at various vacuum levels to tune the MoTe₂ charge carriers between predominantly pristine n-type ambipolar, symmetric ambipolar, unipolar p-type, and degenerate-like ptype. Changes in the MoTe₂ transistor performance were related to the physical and chemical absorption and dissociation of O₂, especially at tellurium vacancy sites. Benzyl viologen doping using optimized dopant concentrations and annealing conditions was used to achieve unipolar n-type MoTe₂ FETs with a high on-off ratio exceeding 10⁶. The dopant concentration and annealing conditions were varied to modulate the electron concentration over a wide range. Furthermore, Al₂O₃ Capping was then introduced to the device surfaces for improving the carrier mobilities. Hole and electron mobilities were improved to 41 cm²/Vs and 80 cm²/Vs respectively after Al₂O₃ capping; they are among the highest carrier mobilities of MoTe₂ transistors ever obtained. A lateral homogeneous MoTe₂ p-n diode was fabricated combining the electron and hole doping techniques, the device displays excellent diode properties with a high rectification ratio of 10⁴ at 0 gate bias and an ideality factor of 1.2.

References

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